

Notice of References Cited	Application/Control No. 10/594,119	Applicant(s)/Patent Under Reexamination SHINYA ET AL.	
	Examiner Leon Y. Lum	Art Unit 1641	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0234229	10-2006	Van Beuningen et al.	435/006
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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FOREIGN PATENT DOCUMENTS

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